STF7N60M2



N-channel 600 V, 0.86 Ω typ., 5 A MDmesh II Plus™ low Q_g Power MOSFET in TO-220FP package

Datasheet - production data

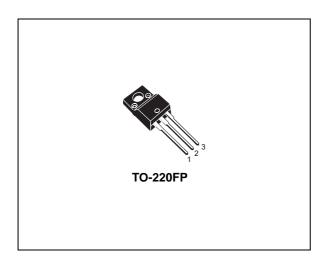
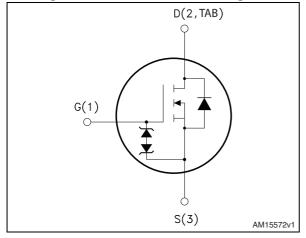


Figure 1. Internal schematic diagram



Features

Order code	V _{DS} @ T _{Jmax}	R _{DS(on)} max	I _D
STF7N60M2	650 V	$0.95~\Omega$	5 A

- Extremely low gate charge
- Lower R_{DS(on)} x area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

Applications

· Switching applications

Description

This device is an N-channel Power MOSFET developed using a new generation of MDmeshTM technology: MDmesh II PlusTM low Q_g . This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

Order code	Marking	Package	Packaging
STF7N60M2	7N60M2	TO-220FP	Tube

Contents STF7N60M2

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STF7N60M2 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I _D	Drain current (continuous) at T _C = 25 °C	5 ⁽¹⁾	Α
I _D	Drain current (continuous) at T _C = 100 °C	3.5 ⁽¹⁾	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	20 ⁽¹⁾	Α
P _{TOT}	Total dissipation at T _C = 25 °C	20	W
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s; T _C =25 °C)	2500	V
dv/dt (2)	Peak diode recovery voltage slope	15	V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	50	V/115
T _{stg}	Storage temperature	- 55 to 150	°C
T _j	Max. operating junction temperature	- 33 (0 150	

^{1.} Pulse width limited by safe operating area.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	6.25	°C/W
R _{thj-amb}	,		°C/W

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	1.5	Α
E _{AS}	Single pulse avalanche energy (starting T_j =25°C, I_D = I_{AR} ; V_{DD} =50)	99	mJ

^{2.} $I_{SD} \le 5$ A, di/dt ≤ 400 A/ μ s; $V_{DS peak} < V_{(BR)DSS}$, V_{DD} =400 V

^{3.} $V_{DS} \le 480 \text{ V}$

Electrical characteristics STF7N60M2

2 **Electrical characteristics**

(T_C = 25 °C unless otherwise specified)

Table 5. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 600 V V _{DS} = 600 V, T _C =125 °C			1 100	μA μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$		0.86	0.95	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	271	-	pF
C _{oss}	Output capacitance	V _{DS} = 100 V, f = 1 MHz,	-	15.7	-	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0$	-	0.68	-	pF
Coss eq. (1)	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$	-	75.5	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	7.2	-	Ω
Qg	Total gate charge	V _{DD} = 480 V, I _D = 5 A,	-	8.8	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V	-	1.8	-	nC
Q _{gd}	Gate-drain charge	(see Figure 15)	-	4.3	-	nC

 $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time		-	7.6	-	ns
t _r	Rise time	$V_{DD} = 300 \text{ V}, I_{D} = 2.5 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 14</i> and <i>19</i>)	-	7.2	-	ns
t _{d(off)}	Turn-off delay time		-	19.3	-	ns
t _f	Fall time		-	15.9	-	ns

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Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current				5	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		_		20	Α
V _{SD} (2)	Forward on voltage $I_{SD} = 5 \text{ A}, V_{GS} = 0$		-		1.6	V
t _{rr}	Reverse recovery time	F A -11/-14 400 A/	-	275		ns
Q _{rr}	Reverse recovery charge	$I_{SD} = 5 \text{ A, di/dt} = 100 \text{ A/µs}$ $V_{DD} = 60 \text{ V (see Figure 19)}$	-	1.55		nC
I _{RRM}	Reverse recovery current	1 July 1 1 (000 / 190/0 / 10)	-	11		Α
t _{rr}	Reverse recovery time	I _{SD} = 5 A, di/dt = 100 A/μs	-	376		ns
Q _{rr}	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 ^{\circ}\text{C}$	-	2.1		nC
I _{RRM}	Reverse recovery current	(see <i>Figure 19</i>)	-	11		Α

^{1.} Pulse width limited by safe operating area.



^{2.} Pulsed: pulse duration = 300 µs, duty cycle 1.5%

Electrical characteristics STF7N60M2

Electrical characteristics (curves) 2.1

Figure 2. Safe operating area

AM15813v1 (A) 10 10µs 100µs 10ms Tj=150°C 0.1 Tc=25°C Single pulse 0.01 10 VDS(V)

Figure 3. Thermal impedance

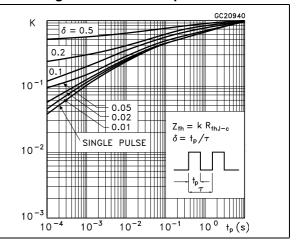


Figure 4. Output characteristics

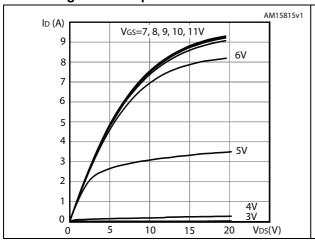


Figure 5. Transfer characteristics

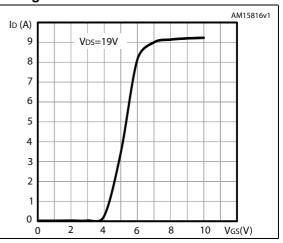
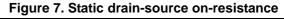
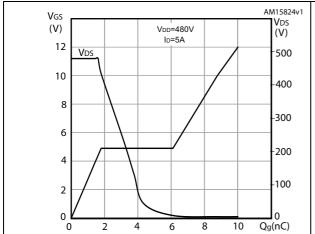
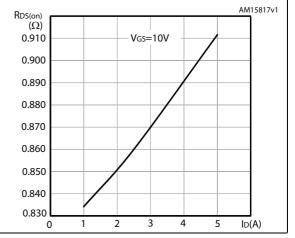


Figure 6. Gate charge vs gate-source voltage





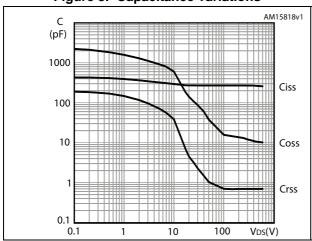


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Figure 8. Capacitance variations

Figure 9. Output capacitance stored energy



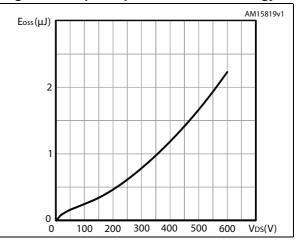
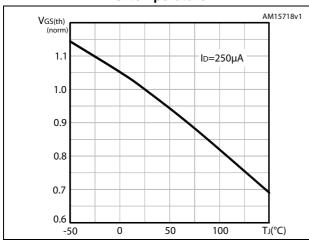


Figure 10. Normalized gate threshold voltage vs. temperature

Figure 11. Normalized on-resistance vs. temperature



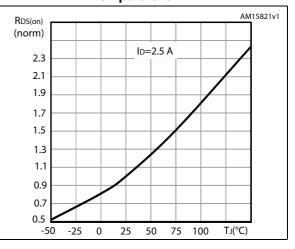
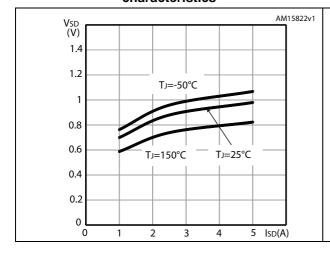
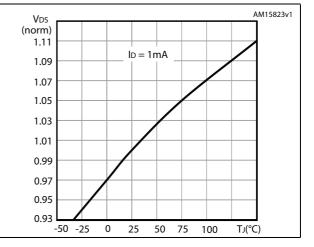


Figure 12. Drain-source diode forward characteristics

Figure 13. Normalized V_{DS} vs. temperature





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Test circuits STF7N60M2

3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

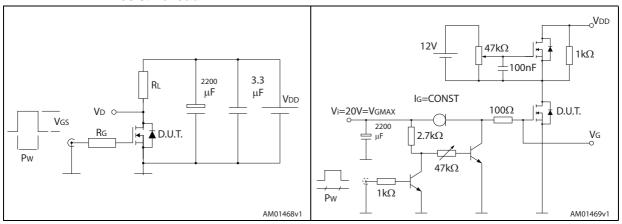


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

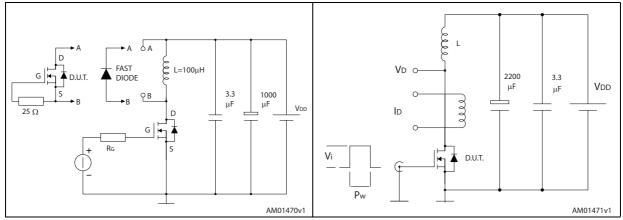
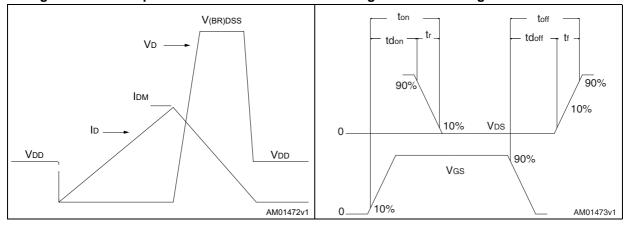


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.



Table 9. TO-220FP mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
А	4.4		4.6
В	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

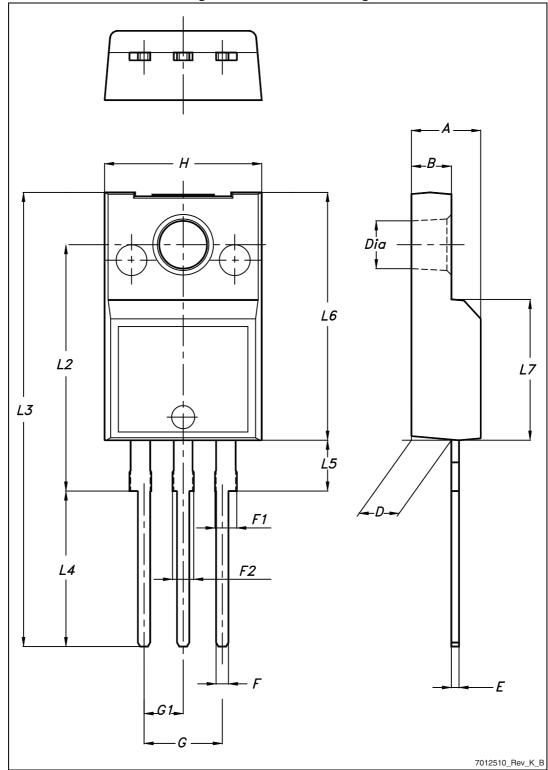


Figure 20. TO-220FP drawing

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Revision history STF7N60M2

5 Revision history

Table 10. Document revision history

Date	Revision	Changes
26-Jun-2013	1	First release.

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